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October 2014

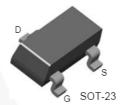
BSS123L N-Channel Logic Level Enhancement Mode Field Effect Transistor

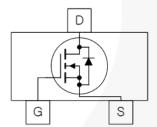
Features

- 0.17 A, 100 V, $R_{DS(ON)}$ = 6 Ω at V_{GS} = 10 V $R_{DS(ON)}$ = 10 Ω at V_{GS} = 4.5 V
- High Density Cell Design for Low R_{DS(ON)}
- · Rugged and Reliable
- Compact Industry Standard SOT-23 Surface Mount Package
- · Very Low Capacitance
- · Fast Switching Speed

Description

This N-channel enhancement mode field effect transistor is produced using high cell density, trench MOSFET technology. This product minimizes on-state resistance while providing rugged, reliable and fast switching performance. This product is particularly suited for low-voltage, low-current applications such as small servo motor control, power MOSFET gate drivers, logic level transistor, high speed line drivers, power management/power supply and switching applications.





Ordering Information

Part Number Marking		Package	Packing Method	
BSS123L	SB	SOT-23 3L	Tape and Reel	

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1

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25^{\circ}$ C unless otherwise noted.

Symbol	Parameter		Value	Unit
V _{DSS}	Drain-Source Voltage		100	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Maximum Drain Current	Continuous	0.17	A
	Maximum Drain Current	Pulsed	0.68	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purposes, 1/16 inch from Case for 10 Seconds		300	°C

Thermal Characteristics

Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	(4)		Unit
Б	Maximum Power Dissipation ⁽¹⁾	0.36	W
P _D	Derate Above 25°C	2.8	mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient ⁽¹⁾	380	°C/W

Note:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 380°C/W when mounted on a minimum pad.

Scale 1: 1 on letter size paper

ESD Rating(2)

Symbol	Parameter	Value	Unit
HBM	Human Body Model per ANSI/ESDA/JEDEC JS-001-2012	50	V
CDM	Charged Device Model per JEDEC C101C	>2000	V

Note:

2. ESD values are in typical, no over-voltage rating is implied, ESD CDM zap voltage is 2000 V maximum.

Electrical Characteristics

Values are at $T_A = 25$ °C unless otherwise noted.

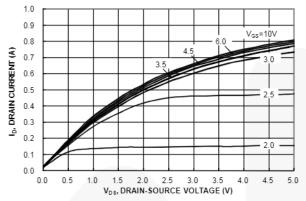
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 μ A	100	103		V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		100		mV/°C
	Zoro Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V		0.027	1	1
I _{DSS}		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V},$ $T_{J} = 125^{\circ}\text{C}$		0.159	60	μΑ
		V _{DS} = 20 V, V _{GS} = 0 V		0.07	10	nA
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V		0.036	50	
I _{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V		-0.019	-50	nA
On Charac	teristics ⁽³⁾					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	0.8	1.405	2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		-2.82		mV/°C
		V _{GS} = 10 V, I _D = 0.17 A		2.98	6	Ω
Raszakii	Static Drain-Source	V _{GS} = 4.5 V, I _D = 0.17 A		3.17	10	
R _{DS(ON)}	On-Resistance	V _{GS} = 10 V, I _D = 0.17 A, T _J = 125°C		5.63	12	
I _{D(ON)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	0.680	0.735		А
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 0.17 A	0.08	2.13		S
Dynamic C	haracteristics			'		
C _{iss}	Input Capacitance			21.5		pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		3.52		pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WH 12		1.67		pF
R _G	Gate Resistance	V _{GS} = 15 V, V _{GS} = 1.0 MHz		7.18		Ω
Switching	Characteristics ⁽³⁾					
t _{d(on)}	Turn-On Delay			2.2	3.4	ns
t _r	Turn-On Rise Time	V _{DD} = 30 V, I _D = 0.28 A,	/	1.7	18	ns
t _{d(off)}	Turn-Off Delay	V_{GS} = 10 V, R_{GEN} = 6 Ω		5.9	31	ns
t _f	Turn-Off Fall Time			5.6	5	ns
Qg	Total Gate Charge	V _{DS} = 25 V, I _D = 0.22 A, V _{GS} = 10 V		0.793	2.5	nC
Q _{gs}	Gate-Source Charge			0.092		nC
Q _{gd}	Gate-Drain Charge			0.171		nC
	rce Diode Characteristics and Ma	ximum Ratings		•		
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 440 mA ⁽¹⁾		0.867	1.3	٧
T _{rr}	Diode Reverse Recovery Time	L = 0.0 A diE/dt = 400 A/-0		11.9		ns
Qrr	Diode Reverse Recovery Charge	$I_F = 0.2 \text{ A, diF/dt} = 100 \text{ A/}\mu\text{S}$		1.3		nC

Note:

3. Pulse test: pulse width \leq 300 $\mu s,$ duty cycle \leq 2.0%.

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Typical Performance Characteristics



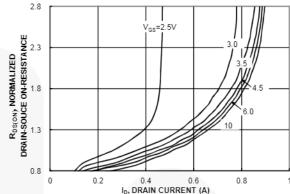
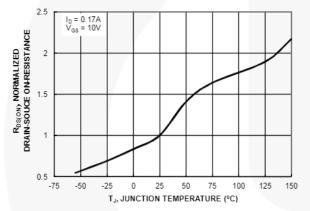


Figure 1. On-Region Characteristics

Figure 2. On-Resistance Variation with Gate Voltage and Drain Current



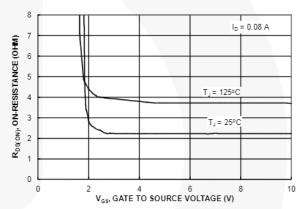
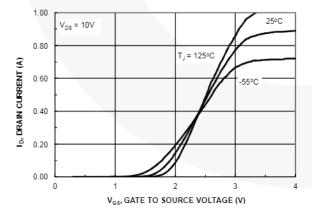


Figure 3. On-Resistance Variation with Temperature

Figure 4. On-Resistance Variation with Gate-to-Source Voltage



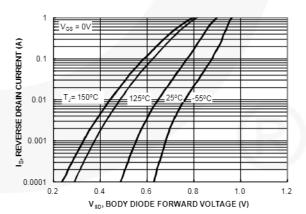


Figure 5. Transfer Characteristics

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Performance Characteristics (Continued) 100 (d) Qg, GATE CHARGE (nC) Figure 7. Gate Charge Characteristics

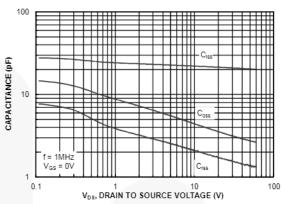
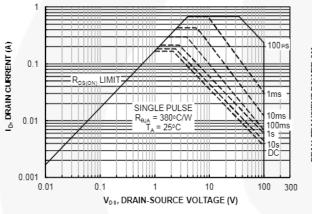


Figure 8. Capacitance Characteristics



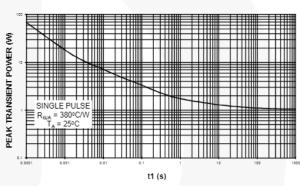


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

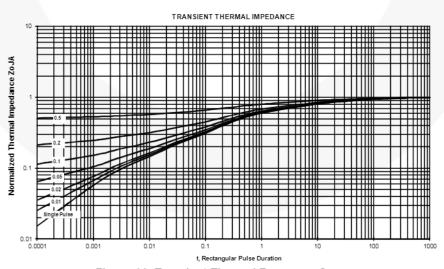
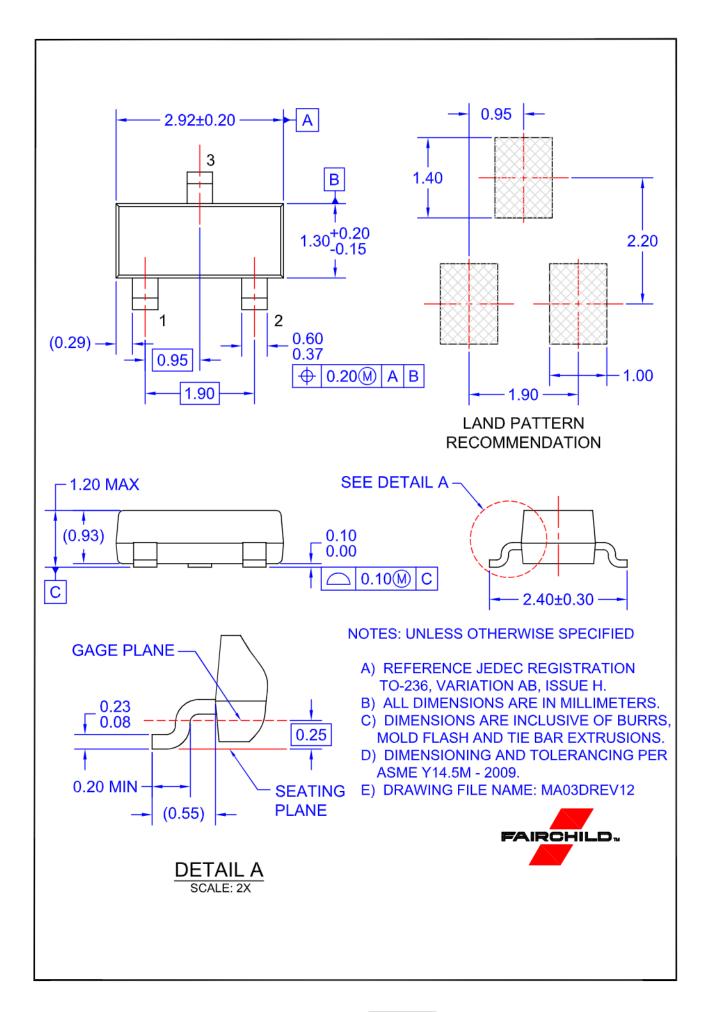


Figure 11. Transient Thermal Response Curve.



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